Search Notes			

Application/Control No.	No. Applicant(s)/Patent under Reexamination	
10/075,051	WANG ET AL.	
Examiner	Art Unit	
Dienane M. Bayard	2141	

SEARCHED					
Class	Subclass	Date	Examiner		
709	217	10/25/2005	DB		
709	226	10/25/2005	DB		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
East		10/25/2005	DB	
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